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NTE2970 MOSFET N-Channel, Enhancement Mode High Speed Switch TO-247 Type Package

Features:

- Low Gate Charge Q_g Results in Simple Drive Requirement
- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current

Applications:

- Switch Mode Power Supply (SMPS)
- Uninterruptable Power Supply
- High Speed Power Switching

Typical SMPS Topologies:

- Full Bridge Converters
- Power factor Correction Boost

Absolute Maximum Ratings: ($T_C = +25^\circ\text{C}$ unless otherwise specified)

Drain-Source Voltage, V_{DS}	500V
Gate-Source Voltage, V_{GS}	$\pm 30\text{V}$
Continuous Drain Current ($V_{GS} = 10\text{V}$), I_D	
$T_C = +25^\circ\text{C}$	22A
$T_C = +100^\circ\text{C}$	14A
Pulsed Drain Current (Note 1), I_{DM}	88A
Single Pulsed Avalanche Energy (Note 2), E_{AS}	1180mJ
Repetitive Avalanche Current (Note 1), I_{AR}	22A
Repetitive Avalanche Energy (Note 1), E_{AR}	28mJ
Total Power Dissipation ($T_C = +25^\circ\text{C}$), P_D	277W
Linear Derating Factor	2.2W/ $^\circ\text{C}$
Peak Diode Recovery dV/dt (Note 3), dV/dt	4.8V/ns
Operating Junction Temperature Range, T_J	-55° to $+150^\circ\text{C}$
Storage Temperature Range, T_{stg}	-55° to $+150^\circ\text{C}$
Lead Temperature (During Soldering, 1.6mm from case, 10 sec.), T_L	$+300^\circ\text{C}$
Maximum Thermal Resistance, Junction-to-Case (Drain), R_{thJC}	0.45 $^\circ\text{C}/\text{W}$
Typical Thermal Resistance, Case-to-Sink (Flat, Greased Surface), R_{thCS}	0.24 $^\circ\text{C}/\text{W}$
Maximum Thermal Resistance, Junction-to-Ambient, R_{thJA}	40 $^\circ\text{C}/\text{W}$
Mounting Torque (6-32 or M3 Screw)	10 lbf • in (1.1 N • m)

Note 1. Repetitive Rating: Pulse Width limited by Maximum Junction Temperature.

Note 2. Starting $T_J = +25^\circ\text{C}$, $L = 4.87\text{mH}$, $I_{AS} = 22\text{A}$, $R_G = 25\Omega$.

Note 3. $I_{SD} \leq 22\text{A}$, $di/dt \leq 190\text{A}/\mu\text{s}$, $V_{DD} \leq V_{DS}$, $T_J \leq +150^\circ\text{C}$.

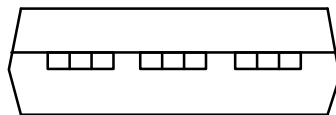
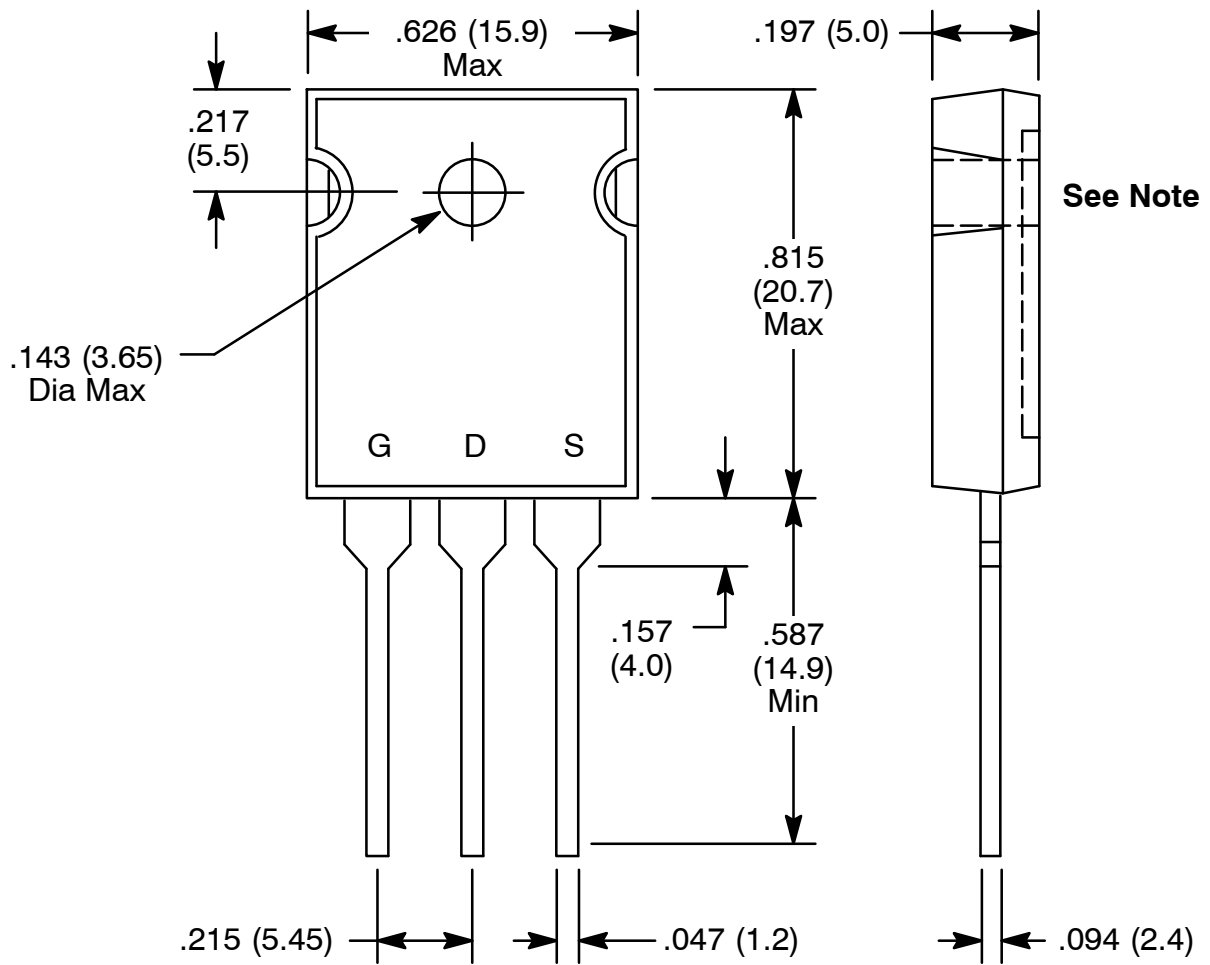
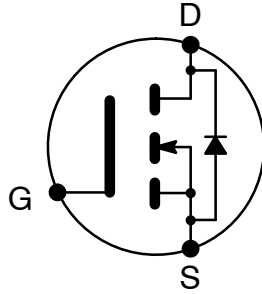
Electrical Characteristics: ($T_J = +25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Static Characteristics						
Drain–Source Breakdown Voltage	V_{DS}	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	500	–	–	V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Referenced to $+25^\circ\text{C}$, $I_D = 1\text{mA}$	–	0.55	–	$\text{V}/^\circ\text{C}$
Gate–Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	2.0	–	4.0	V
Gate–Source Leakage	I_{GSS}	$V_{GS} = \pm 30\text{V}$	–	–	± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 500\text{V}, V_{GS} = 0\text{V}$	–	–	25	μA
		$V_{DS} = 400\text{V}, V_{GS} = 0\text{V}, T_C = +125^\circ\text{C}$	–	–	250	μA
Drain–Source ON Resistance	$R_{DS(on)}$	$V_{GS} = 10\text{V}, I_D = 13\text{A}$, Note 4	–	–	0.23	Ω
Forward Transconductance	g_{fs}	$V_{DS} = 50\text{V}, I_D = 13\text{A}$, Note 4	12	–	–	S
Dynamic Characteristics						
Input Capacitance	C_{iss}	$V_{GS} = 0\text{V}, V_{DS} = 25\text{V}, f = 1\text{MHz}$	–	3450	–	pF
Output Capacitance	C_{oss}		–	513	–	pF
Reverse Transfer Capacitance	C_{rss}		–	27	–	pF
Output Capacitance	C_{oss}	$V_{GS} = 0\text{V}, V_{DS} = 1\text{V}, f = 1\text{MHz}$	–	4935	–	pF
		$V_{GS} = 0\text{V}, V_{DS} = 400\text{V}, f = 1\text{MHz}$	–	137	–	pF
Effective Output Capacitance	$C_{oss\text{eff}}$	$V_{GS} = 0\text{V}, V_{DS} = 0\text{V to } 400\text{V}$, Note 5	–	264	–	pF
Turn–On Delay Time	$t_{d(on)}$	$V_{DD} = 250\text{V}, I_D = 22\text{A}, R_G = 4.3\Omega, R_D = 11\Omega$, Note 4	–	26	–	ns
Rise Time	t_r		–	94	–	ns
Turn–Off Delay Time	$t_{d(off)}$		–	47	–	ns
Fall Time	t_f		–	47	–	ns
Total Gate Charge	Q_g	$V_{DS} = 400\text{V}, V_{GS} = 10\text{V}, I_D = 22\text{A}$, Note 4	–	–	120	nC
Gate–Source Charge	Q_{gs}		–	–	32	nC
Gate–Drain (Miller) Charge	Q_{gd}		–	–	52	nC
Source–Drain Diode Ratings and Characteristics						
Continuous Source Current	I_S	Integral Reverse PN–Diode in the MOSFET	–	–	22	A
Pulsed Source Current (Note 1)	I_{SM}		–	–	88	A
Diode Forward Voltage	V_{SD}	$T_J = +25^\circ\text{C}, I_S = 22\text{A}, V_{GS} = 0\text{V}$, Note 4	–	–	1.5	V
Reverse Recovery Time	t_{rr}	$T_J = +25^\circ\text{C}, I_F = 22\text{A}, dl/dt = 100\text{A}/\mu\text{s}$, Note 4	–	570	850	ns
Reverse Recovery Charge	Q_{rr}		–	6.1	9.2	μC
Forward Turn–On Time	t_{on}	Intrinsic turn–on time is negligible (turn–on is dominated by L_S and L_D)				

Note 1. Repetitive Rating: Pulse Width limited by Maximum Junction Temperature.

Note 4. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.

Note 5. $C_{oss\text{eff}}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0% to 80% V_{DS} .



Note: Pin2 connected to metal part of mounting surface.